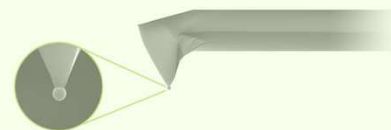




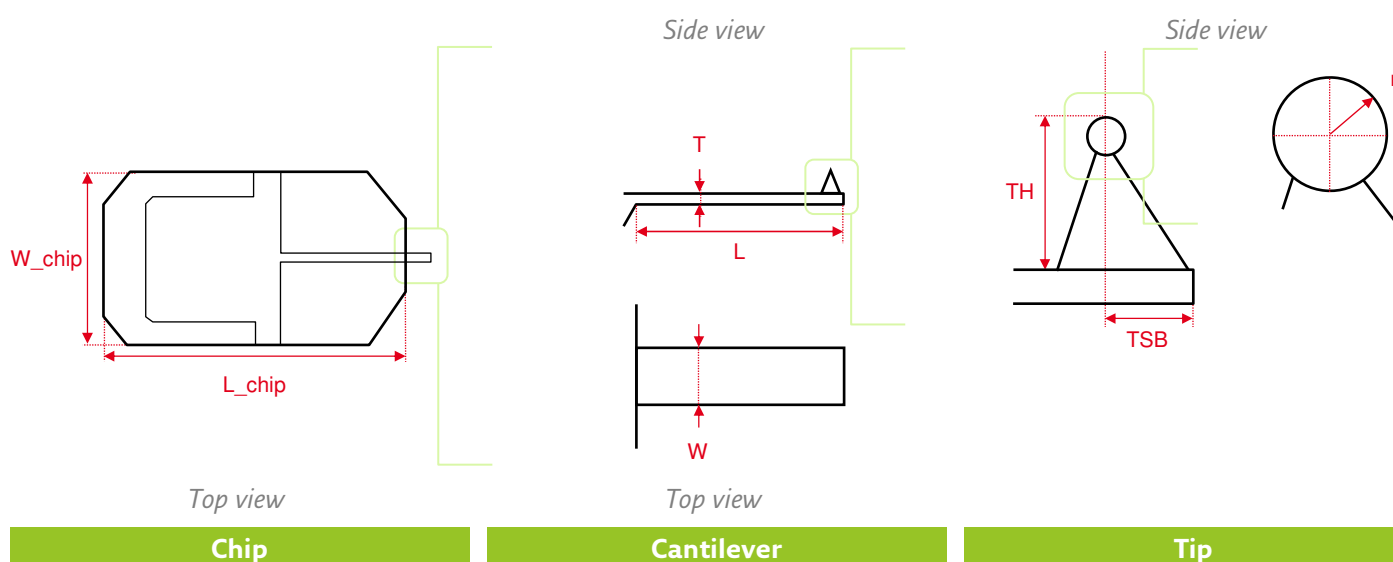
Tip radius / r	k 40 N/m	k 2.8 N/m	k 0.2 N/m
20 nm	NT_B20_v0010	NT_B20_v0020	NT_B20_v0030
30 nm	NT_B30_v0010	NT_B30_v0020	NT_B30_v0030
40 nm	NT_B40_v0010	NT_B40_v0020	NT_B40_v0030
50 nm	NT_B50_v0010	NT_B50_v0020	NT_B50_v0030
100 nm	NT_B100_v0010	NT_B100_v0020	NT_B100_v0030
150 nm	NT_B150_v0010	NT_B150_v0020	NT_B150_v0030
300 nm	NT_B300_v0010	NT_B300_v0020	NT_B300_v0030
500 nm	NT_B500_v0010	NT_B500_v0020	NT_B500_v0030
1000 nm	NT_B1000_v0010	NT_B1000_v0020	NT_B1000_v0030
1500 nm	NT_B1500_v0010	NT_B1500_v0020	NT_B1500_v0030
2000 nm	NT_B2000_v0010	NT_B2000_v0020	NT_B2000_v0030
Cantilever parameter	NCHAu	FMAu	CONTAu
Material	Si	Si	Si
Length / L	125 µm	225 µm	450 µm
Width / W	30 µm	28 µm	50 µm
Thickness / T	4 µm	3 µm	2 µm
Force constant*/ k	40 N/m	2.8 N/m	0.2 N/m
Resonance frequency*/ f	330 kHz	75 kHz	13 kHz
Tip side coating	none	none	none
Back side coating	Au reflex	Au reflex	Au reflex
Total tip height / TH	15 µm	15 µm	15 µm
Tip set back / TSB	15 µm	15 µm	15 µm
Chip parameter			
Length / L_chip	3400 µm	3400 µm	3400 µm
Width / W_chip	1600 µm	1600 µm	1600 µm
Thickness / T_chip	315 µm	315 µm	315 µm
Alignment grooves	yes	yes	yes

biosphere™
carbon AFM probes



- Controlled tip radius
- Pre-calibrated cantilever
- HDC/DLC hardness
- Au reflex coating

Numbers in brackets: guaranteed range | *Cantilever resonance frequency and force constant individually extracted from Laser Doppler Vibrometer (LDV) measurements. Online access to key probe parameters for every individual tip via QR code/TrueDimensions.



For more information, visit
www.nanotools.com

nanotools GmbH
Tölzer Straße 2F
D-81379 Munich
Phone +49 (0)89 12 11 38-0
info@nanotools.com



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